

IN THE CLAIMS:

The following is a complete listing of the claims in this application, reflects all changes currently being made to the claims, and replaces all earlier versions and all earlier listings of the claims:

Claim 1. (previously presented): A stacked photovoltaic element connected to an anode and a cathode, comprising

a plurality of unit photovoltaic elements stacked together in series, each composed of a pn- or pin-junction,

wherein a zinc oxide layer is provided between two consecutively stacked unit photovoltaic elements, and the zinc oxide layer has resistivity varying in a thickness direction thereof, and

wherein both surfaces of the zinc oxide layer are in contact with different unit photovoltaic elements, and a resistivity of the zinc oxide layer on the surface in contact with a unit photovoltaic element away from the anode as seen from the zinc oxide layer is higher than a resistivity of the zinc oxide layer on the surface in contact with a unit photovoltaic element near the anode as seen from the zinc oxide layer.

Claim 2. (original): The stacked photovoltaic element according to Claim 1, wherein zinc oxide of the zinc oxide layer on a side of being in contact with a p-layer of the pn- or pin-junction has a higher resistivity than that on a side of being in contact with an n-layer of the pn- or pin-junction.

Claim 3. (original): The stacked photovoltaic element according to Claim 2, wherein a resistivity of the zinc oxide continuously decreases in the zinc oxide layer from a side of the zinc oxide layer in contact with the p-layer towards a side of the zinc oxide layer in contact with the n-layer.

Claim 4. (currently amended): The stacked photovoltaic element according to Claim 1, wherein a resistivity of zinc oxide of the zinc oxide layer is $2 \times 10^{[[0]]^2} \Omega\text{cm}$ or more but $5 \times 10^{[[3]]^3} \Omega\text{cm}$ or less.

Claim 5. (currently amended): The stacked photovoltaic element according to Claim 1, wherein a high resistant portion of zinc oxide of the zinc oxide layer has $5 \times 10^{[[2]]^2} \Omega\text{cm}$ or more but $5 \times 10^{[[3]]^3} \Omega\text{cm}$ or less.

Claim 6. (original): The stacked photovoltaic element according to Claim 1, wherein at least one of the plurality of the unit photovoltaic elements has a pin-junction comprising an i-type layer composed of amorphous Si:H.

Claim 7. (original): The stacked photovoltaic element according to Claim 1, wherein at least one of the plurality of the unit photovoltaic elements has a pin-junction comprising an i-type layer composed of microcrystalline Si.

Claim 8. (original): The stacked photovoltaic element according to Claim 1, wherein at least one of the plurality of the unit photovoltaic elements has a pin-junction comprising an i-type layer composed of single-crystalline or poly-crystalline Si.

Claims 9. - 11. (canceled)

Claim 12. (currently amended): A method for producing a stacked photovoltaic element comprising an intermediate layer between unit photovoltaic elements each having a pn- or pin-junction, comprising the steps of:

forming a first layer mainly composed of indium oxide on one of the unit photovoltaic elements by performing physical or chemical deposition on [[the]] that unit photovoltaic element; and

forming a second layer mainly composed of zinc oxide on and in direct contact with the first layer by performing physical or chemical deposition on the first layer, wherein the two layers together form the intermediate layer and the second layer is formed at a rate higher than the first layer.

Claim 13. (currently amended): A method for producing a stacked photovoltaic element comprising an intermediate layer between unit photovoltaic elements each having a pn- or pin-junction, comprising the steps of:

forming a first layer mainly composed of indium oxide on at least one of the unit photovoltaic elements by performing physical or chemical deposition on [[the]] that unit photovoltaic element; and

forming a second layer mainly composed of zinc oxide on and in direct contact with the first layer by performing physical or chemical deposition on the first layer, wherein the two layers together form the intermediate layer and the second layer is formed at a temperature lower than the first layer.

Claims 14. - 17. (canceled)